ESTIMATING RICE GROWTH PARAMETERS USING X-BAND SCATTEROMETER DATA

YiHyun Kim¹, SukYoung Hong², Eunyoung Choe³, and Hoonyol Lee⁴

¹National Academy of Agricultural Science, Rural Development Administration, Suwon, Korea, E-mail: yhkim75@korea.kr
²National Academy of Agricultural Science, Rural Development Administration, Suwon, Korea, syhong67@korea.kr
³National Academy of Agricultural Science, Rural Development Administration, Suwon, Korea, eychoe726@korea.kr
⁴Department of Geophysics, Kangwon National University, Chuncheon, Korea, hoonyol@kangwon.ac.kr

ABSTRACT
In this study, we constructed an X-band automatic scatterometer system and analyzed scattering characteristics of paddy rice over the whole period of rice growth from transplanting to harvesting. The backscattering coefficients were calculated from the measured data at incidence angle 45° and full polarization (HH, VV, HV, VH) by applying the radar equation and compared with rice growth data such as plant height, stem number, fresh and dry weight and Leaf Area Index (LAI) that were collected at the same time of each scatterometer measurement. Based on the analysis of the relation between backscattering coefficients at X-band and rice growth parameters, we predicted the rice growth parameters using the radar backscattering data. Relationship between measured and estimated grain dry weight using the X-band backscattering coefficients (VV-polarization) is highly correlated ($R^2=0.94^{***}$). Results from this study show that backscattering coefficients X-band appear effective to estimate rice growth parameters.

Index Terms— X-band, scatterometer, backscattering coefficients, rice, polarization

1. INTRODUCTION
Rice is one of the major crops in Korea and primary food source for more than half of the world’s population. Microwave radar can penetrate cloud cover regardless of weather conditions and can be used day and night. Especially a ground-based polarimetric scatterometer has advantage of monitoring crop conditions continuously using full polarization and various frequencies. Many plant parameters such as leaf area index (LAI), biomass, plant height are highly correlated with backscattering coefficients and according to frequency, polarization between plant parameters [1]–[2]. Kim et. al. (2008) have measured backscattering coefficients of paddy rice using L-, C-, X-band scatterometer system with full polarization and various angles during the rice growth period and have revealed the necessity of near-continuous automatic measurement to eliminate the effect of weather conditions such as wind, moisture [3]. In this paper, thereafter, we analyzed scattering characteristics of paddy rice obtained from X-band automatic scatterometer at the incidence angles of 45° during the whole growth period of the rice and investigated the relationships between scatterometer data and measured ground data such as LAI, plant height, and biomass. Finally, we performed estimation of rice growth parameters using backscattering coefficients.

2. MATERIAL AND METHOD
The study site was located at a National Academy of Agricultural Science (NAAS) experimental field, Suwon, Korea. The rice cultivar was a Japonica type, called Chuchung. The size field was about 660m². The rice seedlings were transplanted in the study site on May 18, 2009 and were harvested on October 12, 2009. We constructed X-band automatic polarimetric scatterometer system which is mainly composed of X-band dual polarimetric square horn antenna with dual-mode transducer, vector network analyzer (VNA), Radio Frequency (RF) cables, RF switch and a personal computer that controls frequency, polarization and data storage (Table 1, Fig 1). This system automatically measures fully-polarimetric backscattering coefficients of rice crop every 10 minutes by RF switch that changes three antennas same interval.
### Table 1. Specification of the X-band automatic scatterometer system.

<table>
<thead>
<tr>
<th>Parameter</th>
<th>Specification</th>
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<tbody>
<tr>
<td>Center Frequency</td>
<td>9.65 GHz</td>
</tr>
<tr>
<td>Bandwidth</td>
<td>1 GHz</td>
</tr>
<tr>
<td>Number of Frequency Points</td>
<td>1601</td>
</tr>
<tr>
<td>Antenna Type</td>
<td>Dual polarimetric square horn</td>
</tr>
<tr>
<td>Antenna Gain</td>
<td>22.4 dB</td>
</tr>
<tr>
<td>Slant Range Resolution</td>
<td>0.15 m</td>
</tr>
<tr>
<td>Wavelength</td>
<td>0.0031 m</td>
</tr>
<tr>
<td>Incident Angle</td>
<td>45°</td>
</tr>
<tr>
<td>Platform Height</td>
<td>4.16 m</td>
</tr>
<tr>
<td>Measurement time</td>
<td>1 per 10 minutes</td>
</tr>
</tbody>
</table>

Fig. 1. View of L, C, X-band automatic scatterometer system.

X-band as high frequency sensitive to heading or grain maturity after heading stage. This phenomenon agrees well with the finding that the peak of radar backscattering temporal plots occurred well before heads began to appear on wheat [5]–[6].

#### 3. RESULTS AND DISCUSSION

Backscattering coefficients of paddy fields at X-band ranged from about -54dB ~ -8dB. HH-, VV polarization backscattering coefficients steadily increased toward panicle formation stage and thereafter decreased and again increased near the harvesting season (Fig. 2). Fresh weight was decreased and heads of the canopy were easily shown, so Polarimetric scatterometer provides a time domain radar return from a target as a fully polarimetric (HH, HV, VH, VV) amplitude and phase data. The system is calibrated using a calibration kit (SmA, 85052D). Growth data for the rice canopy, such as LAI, fresh and dry weight and plant height, were acquired once every week by destructive sampling. Backscattering coefficients were calculated by applying radar equation [4].

We conducted a correlation analysis between the backscattering coefficients from X-band and rice growth variables (Table 2). Backscattering coefficients in X-band were weakly correlated with LAI and biomass but grain weight which related with rice yield was highly correlated with backscattering coefficients with VV polarization. Based on the analysis of between backscattering coefficients in each band and rice growth parameters, we performed prediction of the rice growth parameters. Relationship between backscattering coefficients in X-band (VV, 45°) and grain weight were closely correlated (R² = 0.94).

Table 2. Correlation analysis between backscattering coefficients at X-band and rice growth parameters.

<table>
<thead>
<tr>
<th>VV</th>
<th>HH</th>
<th>HV/VH</th>
</tr>
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<tbody>
<tr>
<td>LAI</td>
<td>Tfw</td>
<td>Gdw</td>
</tr>
<tr>
<td></td>
<td>(g/m²)</td>
<td>(g/m²)</td>
</tr>
<tr>
<td>0.66</td>
<td>0.73***</td>
<td>0.94**</td>
</tr>
</tbody>
</table>

Tfw : Total fresh weight, Gdw : Grain dry weight

* : level of significance p<0.05
** : level of significance p<0.01
*** : level of significance p<0.001

This result suggests that high frequency microwave may barely penetrate the rice canopy, therefore, backscattering
coefficients contain little information on volumetric characteristics such as biomass and LAI.
We compared with measured grain weight (2008 year) and predicted grain weight by modeling. Relationship between measured and predicted grain weight was positive correlated (Fig. 3).

\[ y = 1.1099x - 1.3067 \]
\[ R^2 = 0.96^{***} \]
\[ \text{RMSE} = 1.7685 \]

Fig. 3. Comparison between measured grain (2008 year) and predicted grain weight by modeling (2009 year).

4. CONCLUSIONS

Backscattering coefficients of rice crop were investigated with an automatically-operating ground-based scatterometer. The temporal variations of the backscattering coefficients of the rice crop at X-band during a rice growth period. We conducted the relationship between backscattering coefficients with X-band and rice growth parameters. Grain weight was correlated with backscattering coefficients with VV polarization in X-band. We analyzed comparison between measured growth parameters and predicted growth parameter using scattering model. From this result, polarimetric scatterometer data appear positive to rice growth variables and growth monitoring.

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REFERENCES